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Form PTO-1449				Complete if Known			
US DEPARTMENT OF COMMERCE MAR 1 2 2004			2004	Application Number	10/790,305		
INTEGRALATION DIVINIS				Filing Date March 1, 2004			
INFORMATION DISCLOSURE STATEMENT BY APPLICANT				First Named Inventor Toshihiro KOBAYASHI			
				Art Unit			
. (use as many sheets as necessary)				Examiner Name			
( and the many streets at necessary)			• • • • • • • • • • • • • • • • • • • •	Confirmation No.			
Sheet	11	of	1	Attorney Docket No.	939_058		

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Date Considered: 7-78-05	Examiner:	Sleph on Gravm'	7-28-05

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

<sup>\*</sup>In accordance with the Notice dated July 11, 2003 on the PTO website, we are not enclosing copies of any of the U.S. references listed above.